

**Amendment and Response**

Applicant: Werner Ertle et al.

Serial No.: 10/522,502

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Title: SEMICONDUCTOR WAFER WITH ELECTRICALLY CONNECTED CONTACT AND TEST AREAS

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**IN THE SPECIFICATION**

Please amend the paragraph beginning on line 10 of page 11 as follows:

After testing on the test window 32, the latter is sealed with a protective layer (~~not illustrated here~~) 50.